

# Erratum

As authors of the paper on "Monitoring Environmental Tests by Coulometric Reduction of Metallic Control Samples" (*Journal of Testing and Evaluation*, Vol. 17, No. 6, Nov. 1989, pp. 357-367), we call your attention to a discrepancy between the definition of the "K" factor in Eqs 3 and 4 and the values of this factor, for a number of substances, that are listed in Table 1 of our paper.

These values had originally been given in terms of Angstrom units ( $10^{-8}$  cm) for the film thicknesses ( $T$ )—in line with the cited literature references—and had been defined as such in both the initial and revised (per reviewers' comments) manuscripts. However, at a certain point before publication, Eqs 3 and 4 were modified to give the thickness in terms of nanometers ( $10^{-7}$  cm), which is apparently the presently more acceptable SI unit. The "K" factor values in Table 1 of our paper must therefore be

TABLE 1—"K" factors for thickness calculations.

	Literature Values ( $T$ in Angstrom Units)	SI Values ( $T$ in Nanometres)
AgCl	26.7	2.67
Ag <sub>2</sub> S	17.5	1.75
Cu <sub>2</sub> O	12.4	1.24
CuO	6.43	0.64
Cu <sub>2</sub> S	14.7	1.47

divided by 10 to bring them into line with the new SI terminology. Table 1 above shows these corrections.

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